

# FDP8N50NZ / FDPF8N50NZT

## N-Channel MOSFET

500V, 8A, 0.85Ω

### Features

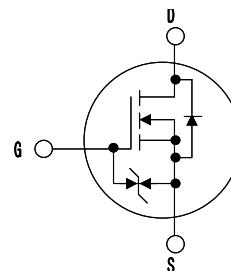
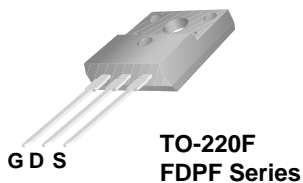
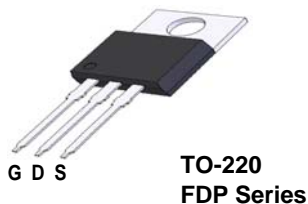
- $R_{DS(on)} = 0.77\Omega$  (Typ.) @  $V_{GS} = 10V, I_D = 4A$
- Low Gate Charge (Typ. 14nC)
- Low  $C_{rss}$  (Typ. 5pF)
- Fast Switching
- 100% Avalanche Tested
- Improve dv/dt Capability
- ESD Improved Capability
- RoHS Compliant



### Description

This N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.



### MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDP8N50NZ	FDPF8N50NZT	Units
$V_{DSS}$	Drain to Source Voltage	500		V
$V_{GSS}$	Gate to Source Voltage	±25		V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ\text{C}$ )	8	8*
		-Continuous ( $T_C = 100^\circ\text{C}$ )	4.8	4.8*
$I_{DM}$	Drain Current	- Pulsed (Note 1)	30	30*
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	122		mJ
$I_{AR}$	Avalanche Current (Note 1)	8		A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	13.9		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	10		V/ns
$P_D$	Power Dissipation	( $T_C = 25^\circ\text{C}$ )	139	50
		- Derate above $25^\circ\text{C}$	1.1	0.4
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150		$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300		$^\circ\text{C}$

\*Drain current limited by maximum junction temperature

### Thermal Characteristics

Symbol	Parameter	FDP8N50NZ	FDPF8N50NZT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.96	3.1	$^\circ\text{C/W}$
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP8N50NZ	FDP8N50NZ	TO-220	-	-	50
FDPF8N50NZT	FDPF8N50NZT	TO-220F	-	-	50

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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### Off Characteristics

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_C = 25^\circ\text{C}$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.5	-	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}, V_{GS} = 0\text{V}$ $V_{DS} = 400\text{V}, T_C = 125^\circ\text{C}$	-	-	1 10	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 25\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 10$	$\mu\text{A}$

### On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 4\text{A}$	-	0.77	0.85	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 20\text{V}, I_D = 4\text{A}$ (Note 4)	-	6.3	-	S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	565	735	pF
$C_{oss}$	Output Capacitance		-	80	105	pF
$C_{rss}$	Reverse Transfer Capacitance		-	5	10	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DS} = 400\text{V}, I_D = 8\text{A}$ $V_{GS} = 10\text{V}$ (Note 4, 5)	-	14	18	nC
$Q_{gs}$	Gate to Source Gate Charge		-	4	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	6	-	nC

### Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 250\text{V}, I_D = 8\text{A}$ $R_G = 25\Omega, V_{GS} = 10\text{V}$ (Note 4, 5)	-	17	45	ns
$t_r$	Turn-On Rise Time		-	34	80	ns
$t_{d(off)}$	Turn-Off Delay Time		-	43	95	ns
$t_f$	Turn-Off Fall Time		-	27	60	ns

### Drain-Source Diode Characteristics

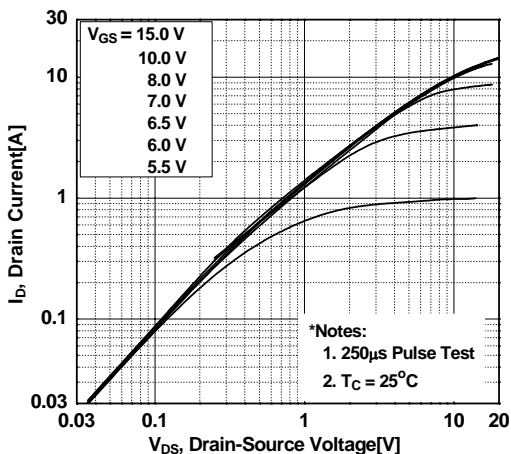
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	8	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	30	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 8\text{A}$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 8\text{A}$	-	300	-	ns
$Q_{rr}$	Reverse Recovery Charge	$di_F/dt = 100\text{A}/\mu\text{s}$ (Note 4)	-	1.9	-	$\mu\text{C}$

#### Notes:

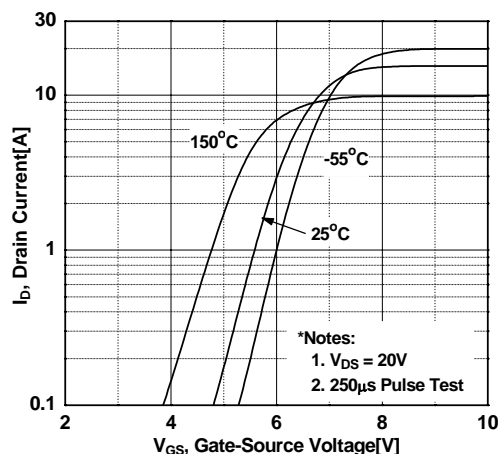
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 3.8\text{mH}, I_{AS} = 8\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 8\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

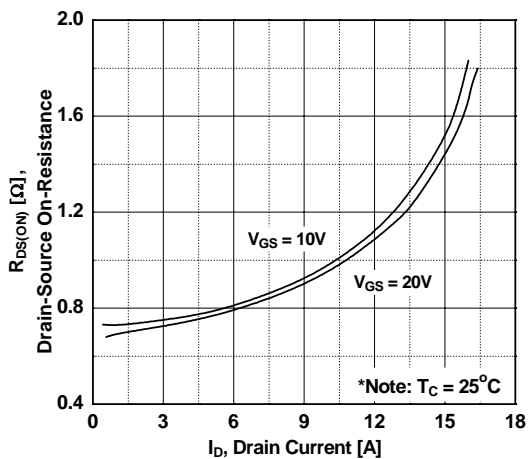
**Figure 1. On-Region Characteristics**



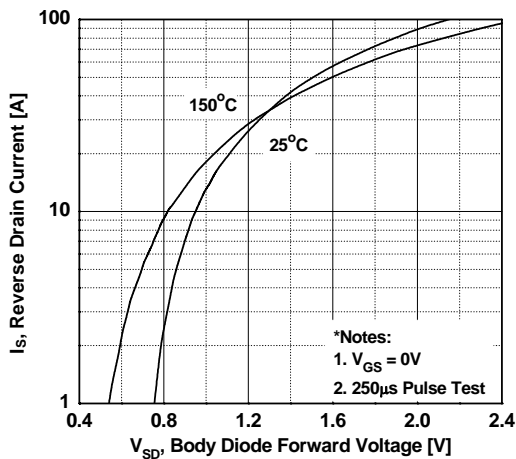
**Figure 2. Transfer Characteristics**



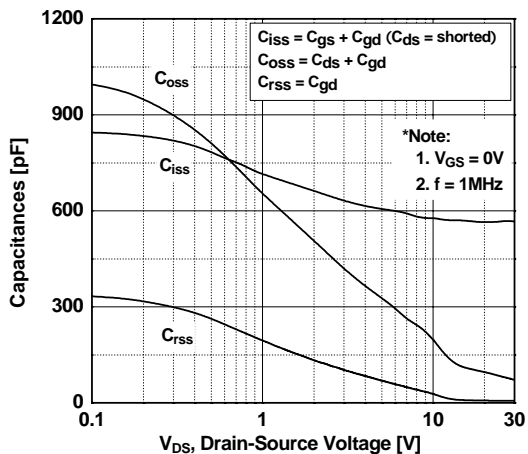
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



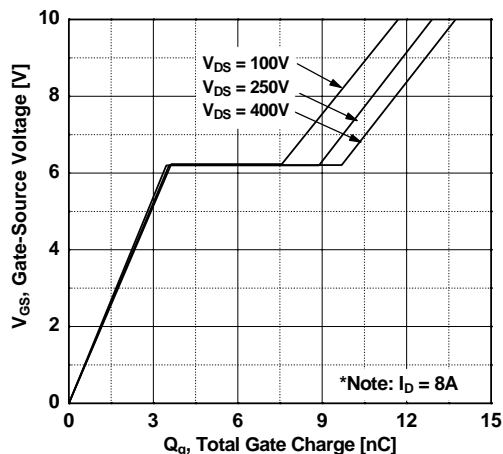
**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**



**Figure 5. Capacitance Characteristics**



**Figure 6. Gate Charge Characteristics**



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

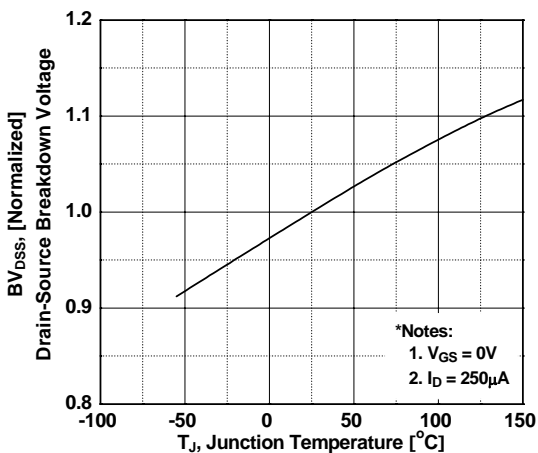


Figure 8. On-Resistance Variation vs. Temperature

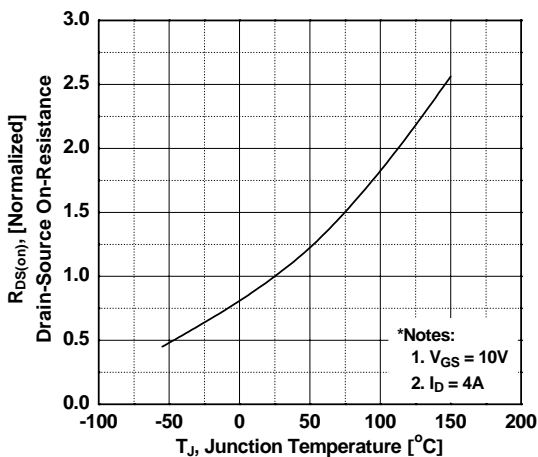


Figure 9. Maximum Safe Operating Area - FDP8N50NZ

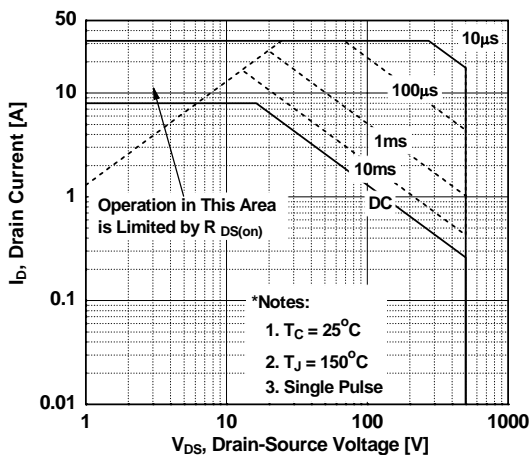


Figure 10. Maximum Safe Operating Area - FDPF8N50NZT

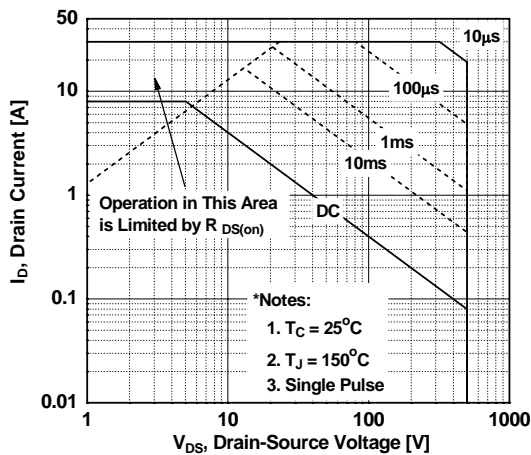
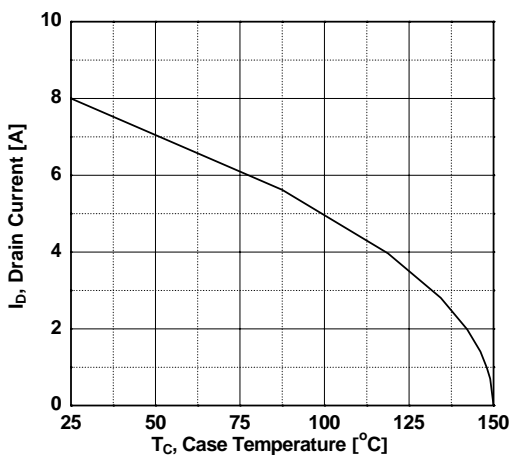


Figure 11. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve - FDP8N50NZ

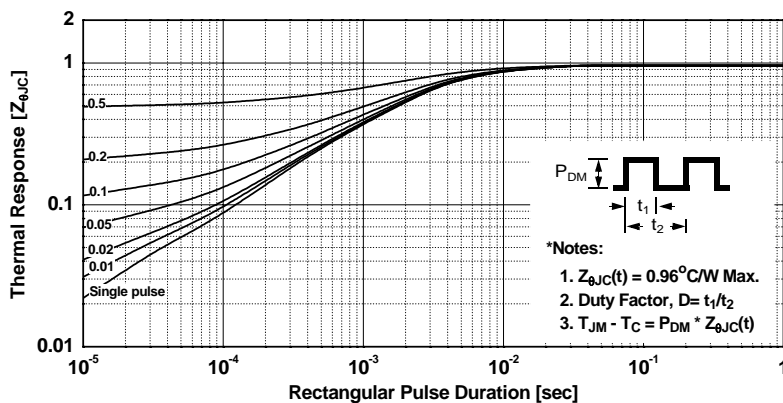
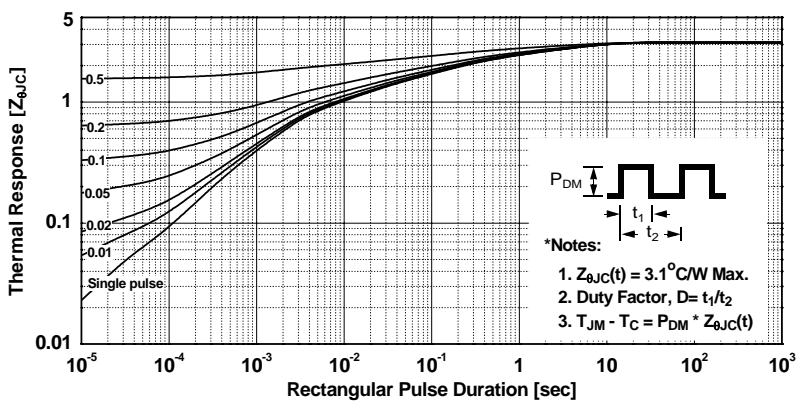
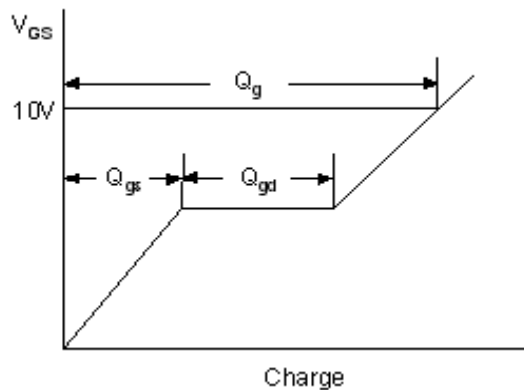
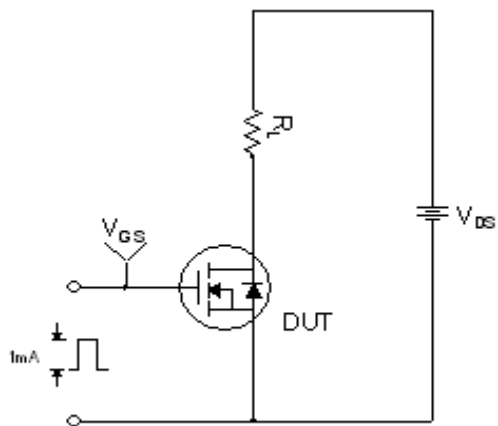


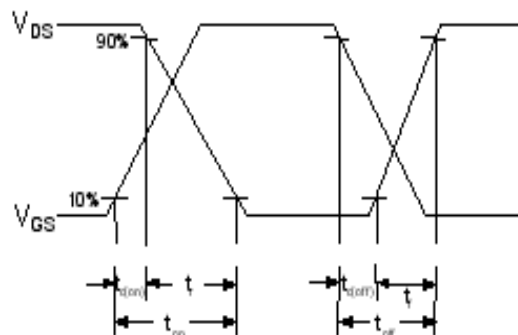
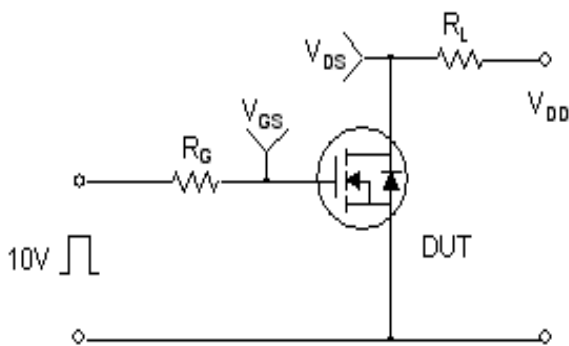
Figure 13. Transient Thermal Response Curve - FDPF8N50NZT



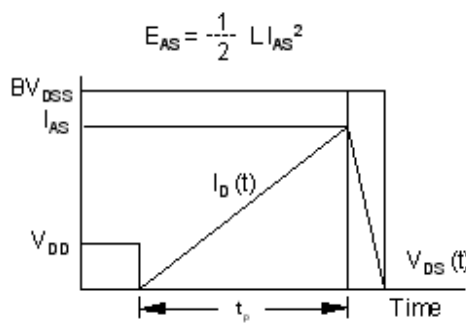
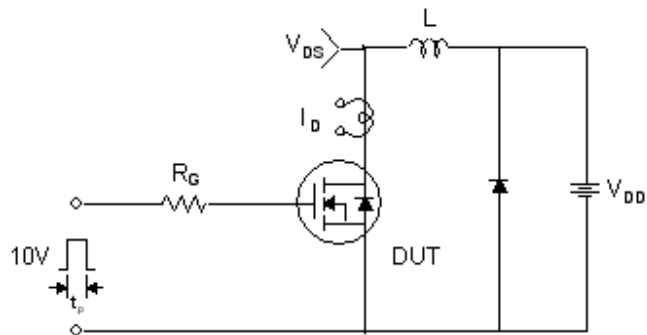
**Gate Charge Test Circuit & Waveform**



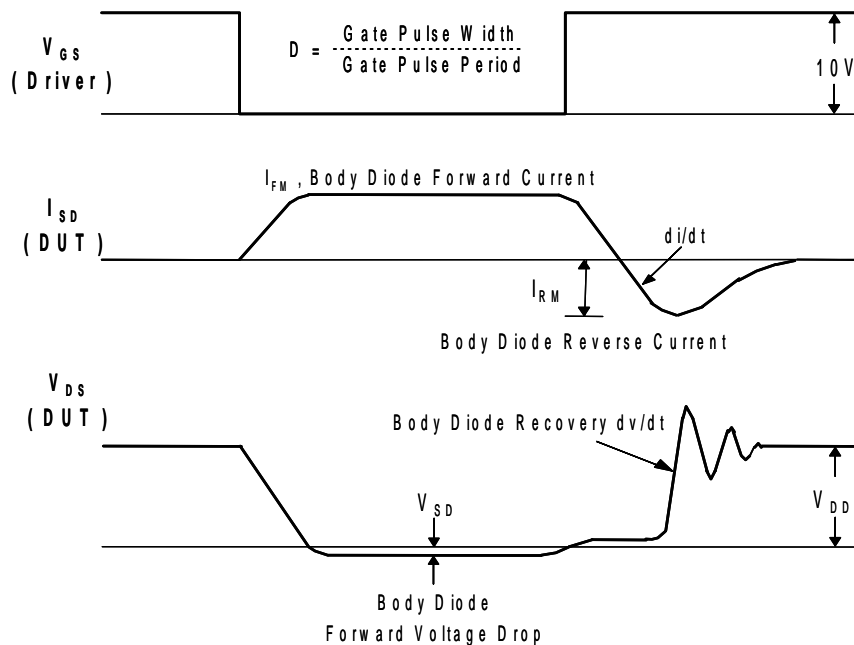
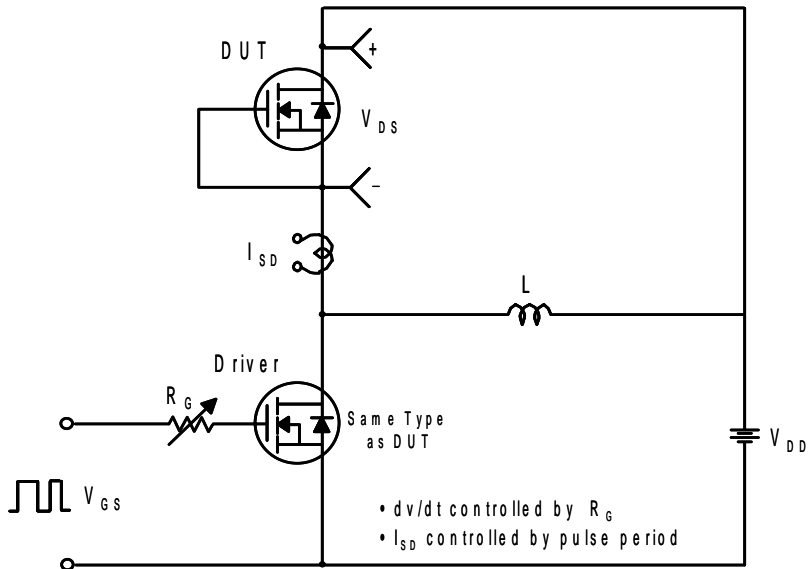
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

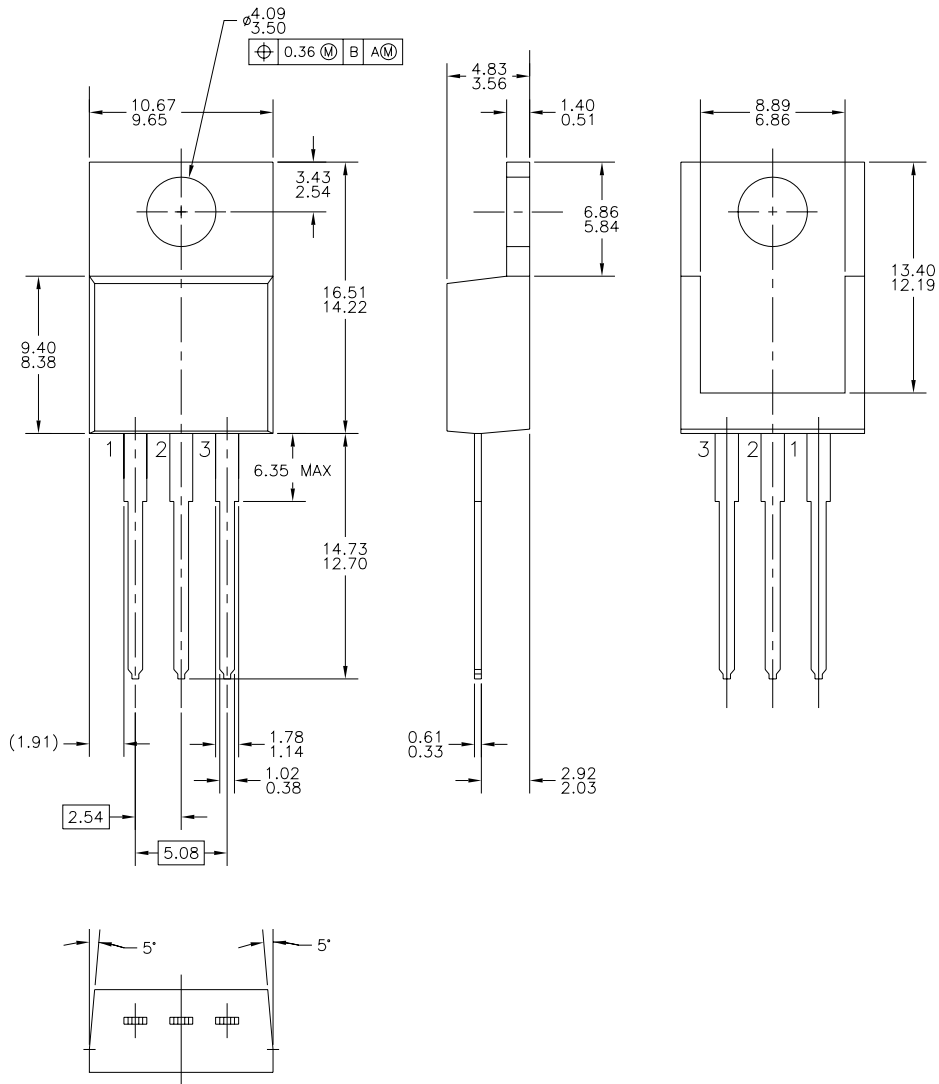


Peak Diode Recovery dv/dt Test Circuit & Waveforms



# Mechanical Dimensions

## TO-220

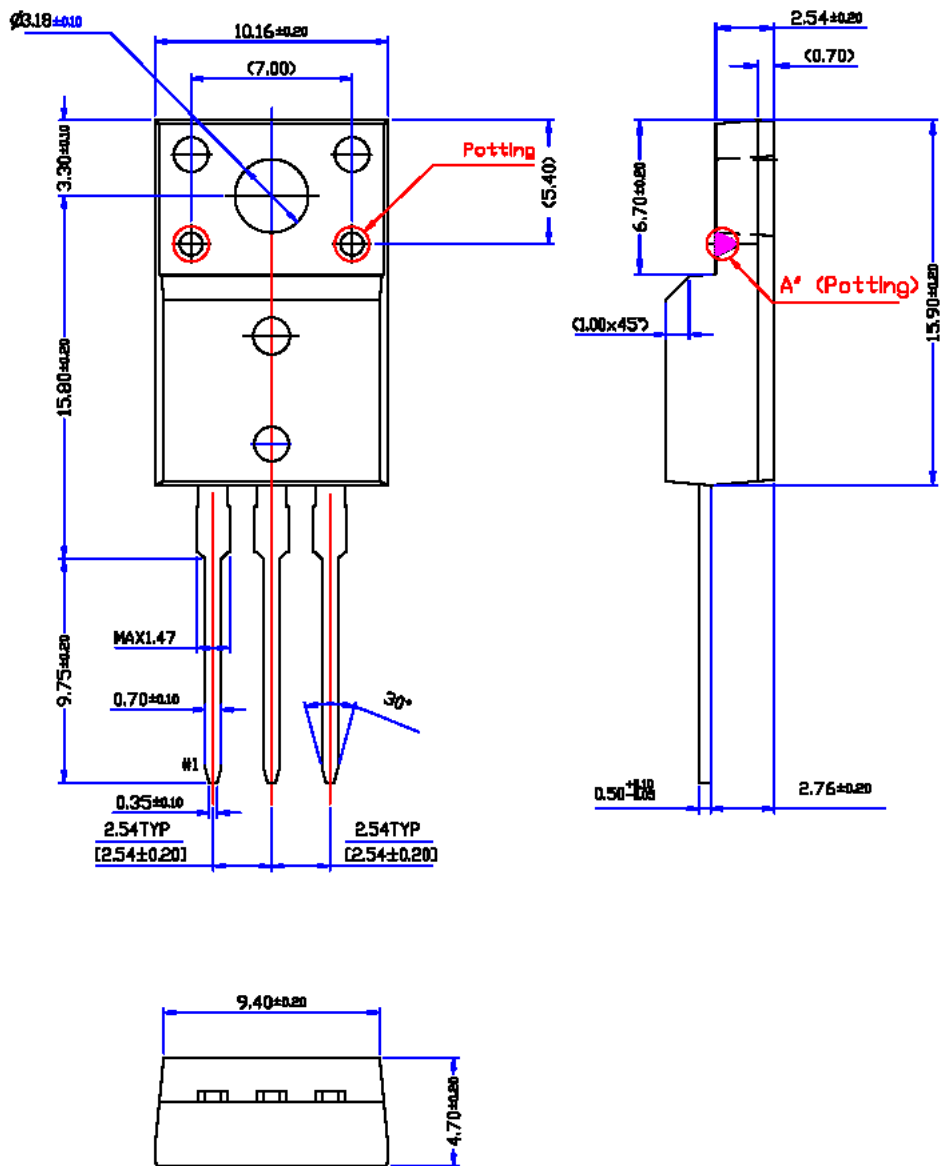


FDP8N50NZ / FDPF8N50NZT N-Channel MOSFET



Package Dimensions

TO-220F Potted









\* Front/Back Side Isolation Voltage : 4000V

Dimensions in Millimeters



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